

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/734,440	SAMPATH ET AL.	
Examiner	Art Unit	
Shick C. Hom	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (USPT, US-PGPUB) - See search History Printout	6/23/2007	SH	
Inventor search - See search printout	6/22/2007	SH	
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